

# GSS6982

## DUAL N-CANNEL ENHANCEMENT MODE POWER MOSFET

CH1	BV <sub>DSS</sub>	30V
	R <sub>DS(ON)</sub>	18mΩ
	I <sub>D</sub>	8.5A
CH2	BV <sub>DSS</sub>	30V
	R <sub>DS(ON)</sub>	26mΩ
	I <sub>D</sub>	7.3A

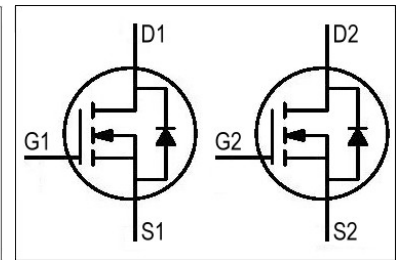
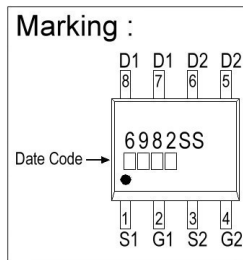
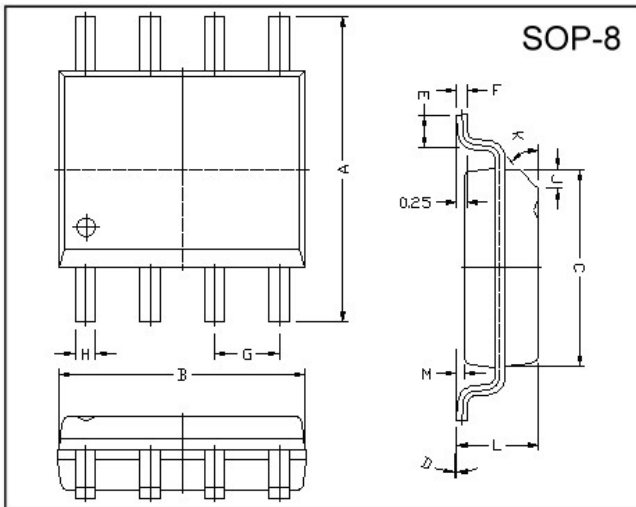
### Description

The GSS6982 provide the designer with the best combination of fast switching, ruggedized device design, ultra low on-resistance and cost-effectiveness.

### Features

- \*Low On-resistance
- \*Fast Switching

### Package Dimensions



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	5.80	6.20	M	0.10	0.25
B	4.80	5.00	H	0.35	0.49
C	3.80	4.00	L	1.35	1.75
D	0°	8°	J	0.375 REF.	
E	0.40	0.90	K	45°	
F	0.19	0.25	G	1.27 TYP.	

### Absolute Maximum Ratings

Parameter	Symbol	Ratings		Unit
		CH-1	CH-2	
Drain-Source Voltage	V <sub>DS</sub>	30	30	V
Gate-Source Voltage	V <sub>GS</sub>	±25	±25	V
Continuous Drain Current <sup>3</sup>	I <sub>D</sub> @TA=25°C	8.5	7.3	A
Continuous Drain Current <sup>3</sup>	I <sub>D</sub> @TA=70°C	6.8	5.8	A
Pulsed Drain Current <sup>1</sup>	I <sub>DM</sub>	30	30	A
Total Power Dissipation	P <sub>D</sub> @TA=25°C	2.0		W
Linear Derating Factor		0.016		W/°C
Operating Junction and Storage Temperature Range	T <sub>j</sub> , T <sub>stg</sub>	-55 ~ +150		°C

### Thermal Data

Parameter	Symbol	Value	Unit
Thermal Resistance Junction-ambient <sup>3</sup> Max.	R <sub>thj-a</sub>	62.5	°C/W

**CH-1 Electrical Characteristics (T<sub>j</sub> = 25°C unless otherwise specified)**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	-	-	V	V <sub>GS</sub> =0, I <sub>D</sub> =250uA
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS} / \Delta T_j$	-	0.03	-	V/°C	Reference to 25°C, I <sub>D</sub> =1mA
Gate Threshold Voltage	V <sub>GS(th)</sub>	1.0	-	3.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA
Forward Transconductance	g <sub>fs</sub>	-	12	-	S	V <sub>DS</sub> =10V, I <sub>D</sub> =8A
Gate-Source Leakage Current	I <sub>GSS</sub>	-	-	±100	nA	V <sub>GS</sub> = ±25V
Drain-Source Leakage Current(T <sub>j</sub> =25°C)	I <sub>DSS</sub>	-	-	1	uA	V <sub>DS</sub> =30V, V <sub>GS</sub> =0
Drain-Source Leakage Current(T <sub>j</sub> =70°C)		-	-	25	uA	V <sub>DS</sub> =24V, V <sub>GS</sub> =0
Static Drain-Source On-Resistance <sup>2</sup>	R <sub>DS(ON)</sub>	-	15	18	mΩ	V <sub>GS</sub> =10V, I <sub>D</sub> =8A
			23	30		V <sub>GS</sub> =4.5V, I <sub>D</sub> =6A
Total Gate Charge <sup>2</sup>	Q <sub>g</sub>	-	14	22	nC	I <sub>D</sub> =8A V <sub>DS</sub> =24V V <sub>GS</sub> =4.5V
Gate-Source Charge	Q <sub>gs</sub>	-	4	-		
Gate-Drain ("Miller") Change	Q <sub>gd</sub>	-	8	-		
Turn-on Delay Time <sup>2</sup>	T <sub>d(on)</sub>	-	12	-	ns	V <sub>DS</sub> =15V I <sub>D</sub> =1A V <sub>GS</sub> =10 R <sub>G</sub> =3.3Ω R <sub>D</sub> =15Ω
Rise Time	T <sub>r</sub>	-	7	-		
Turn-off Delay Time	T <sub>d(off)</sub>	-	25	-		
Fall Time	T <sub>f</sub>	-	9	-		
Input Capacitance	C <sub>iss</sub>	-	1050	1680	pF	V <sub>GS</sub> =0V V <sub>DS</sub> =25V f=1.0MHz
Output Capacitance	C <sub>oss</sub>	-	240	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	165	-		
Gate Resistance	R <sub>g</sub>	-	1.6	2.4	Ω	f=1.0MHz

**Source-Drain Diode**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Forward On Voltage <sup>2</sup>	V <sub>SD</sub>	-	-	1.2	V	I <sub>S</sub> =1.7A, V <sub>GS</sub> =0V
Reverse Recovery Time <sup>2</sup>	T <sub>rr</sub>	-	23	-	ns	I <sub>S</sub> =8A, V <sub>GS</sub> =0V di/dt=100A/μs
Reverse Recovery Charge	Q <sub>rr</sub>	-	15	-	nC	

Notes: 1. Pulse width limited by Max. junction temperature.

2. Pulse width ≤ 300us, duty cycle ≤ 2%.

3. Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board, t ≤ 10sec; 135°C/W when mounted on Min. copper pad.

**CH-2 Electrical Characteristics (T<sub>j</sub> = 25°C unless otherwise specified)**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	$BV_{DSS}$	30	-	-	V	$V_{GS}=0, I_D=250\mu A$
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS} / \Delta T_j$	-	0.03	-	V/°C	Reference to 25°C, $I_D=1mA$
Gate Threshold Voltage	$V_{GS(th)}$	1.0	-	3.0	V	$V_{DS}=V_{GS}, I_D=250\mu A$
Forward Transconductance	$g_{fs}$	-	10	-	S	$V_{DS}=10V, I_D=7A$
Gate-Source Leakage Current	$I_{GSS}$	-	-	±100	nA	$V_{GS}= \pm 25V$
Drain-Source Leakage Current(T <sub>j</sub> =25°C)	$I_{DSS}$	-	-	1	uA	$V_{DS}=30V, V_{GS}=0$
Drain-Source Leakage Current(T <sub>j</sub> =70°C)		-	-	25	uA	$V_{DS}=24V, V_{GS}=0$
Static Drain-Source On-Resistance <sup>2</sup>	$R_{DS(on)}$	-	22	26	mΩ	$V_{GS}=10V, I_D=7A$
			36	45		$V_{GS}=4.5V, I_D=5A$
Total Gate Charge <sup>2</sup>	$Q_g$	-	9	15	nC	$I_D=7A$ $V_{DS}=24V$ $V_{GS}=4.5V$
Gate-Source Charge	$Q_{gs}$	-	3	-		
Gate-Drain ("Miller") Change	$Q_{gd}$	-	5	-		
Turn-on Delay Time <sup>2</sup>	$T_{d(on)}$	-	9	-	ns	$V_{DS}=15V$ $I_D=1A$ $V_{GS}=10$ $R_G=3.3\Omega$ $R_D=15\Omega$
Rise Time	$T_r$	-	6	-		
Turn-off Delay Time	$T_{d(off)}$	-	19	-		
Fall Time	$T_f$	-	6	-		
Input Capacitance	$C_{iss}$	-	640	1030	pF	$V_{GS}=0V$ $V_{DS}=25V$ $f=1.0MHz$
Output Capacitance	$C_{oss}$	-	150	-		
Reverse Transfer Capacitance	$C_{rss}$	-	105	-		
Gate Resistance	$R_g$	-	1.7	2.5	Ω	$f=1.0MHz$

**Source-Drain Diode**

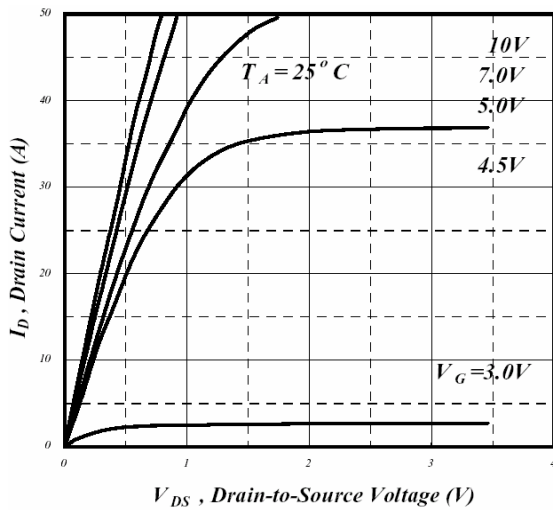
Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Forward On Voltage <sup>2</sup>	$V_{SD}$	-	-	1.2	V	$I_S=1.7A, V_{GS}=0V$
Reverse Recovery Time <sup>2</sup>	$T_{rr}$	-	18	-	ns	$I_S=7A, V_{GS}=0V$ $di/dt=100A/\mu s$
Reverse Recovery Charge	$Q_{rr}$	-	8	-	nC	

Notes: 1. Pulse width limited by Max. junction temperature.

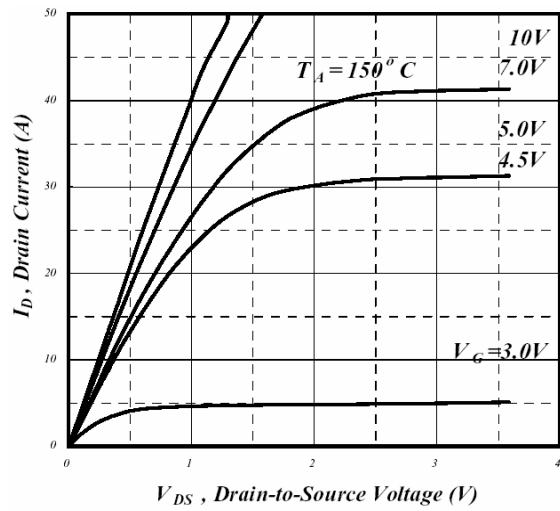
2. Pulse width ≤ 300us, duty cycle ≤ 2%.

3. Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board, t ≤ 10sec; 135°C/W when mounted on Min. copper pad.

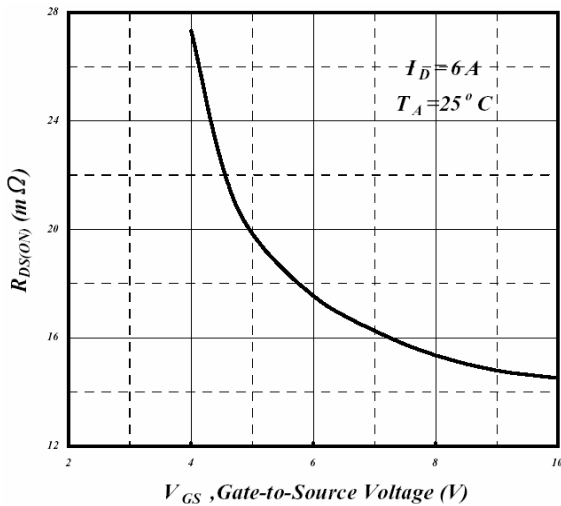
## Characteristics Curve CH-1



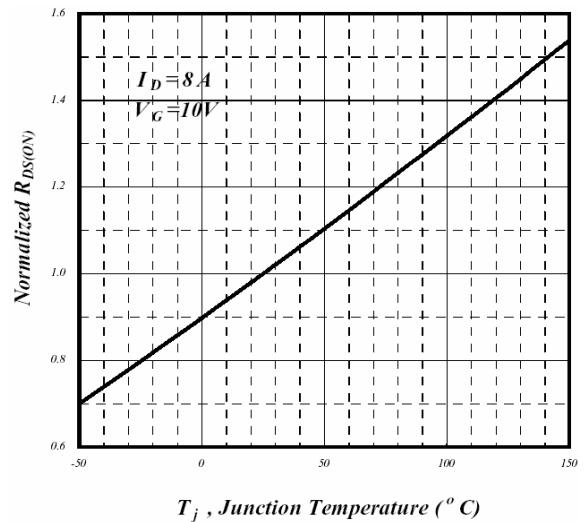
**Fig 1. Typical Output Characteristics**



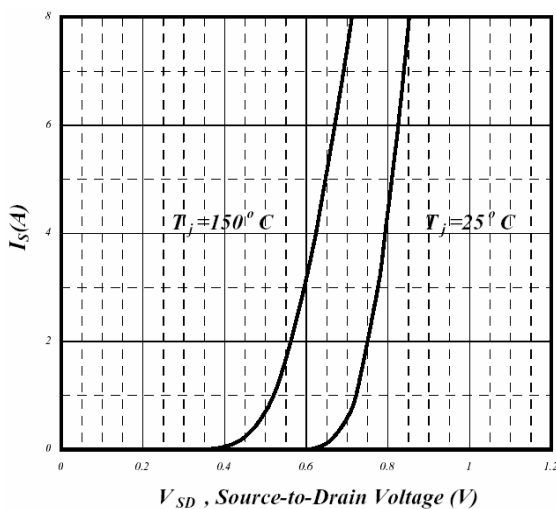
**Fig 2. Typical Output Characteristics**



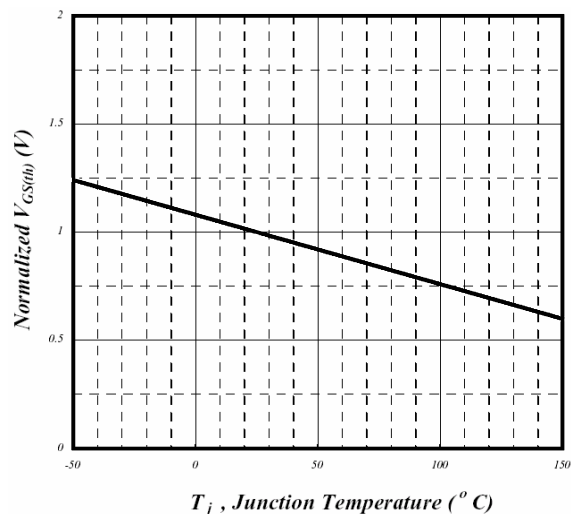
**Fig 3. On-Resistance v.s. Gate Voltage**



**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



**Fig 5. Forward Characteristics of Reverse Diode**



**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**

## CH-1

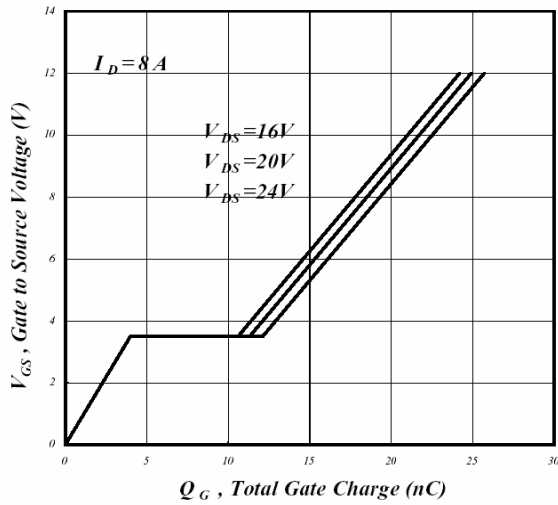


Fig 7. Gate Charge Characteristics

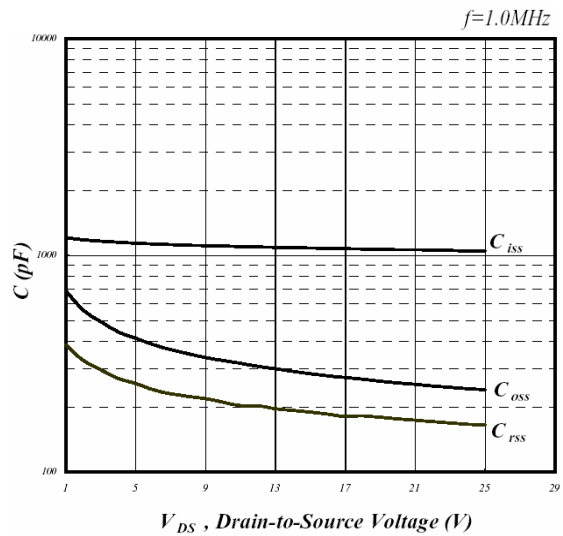


Fig 8. Typical Capacitance Characteristics

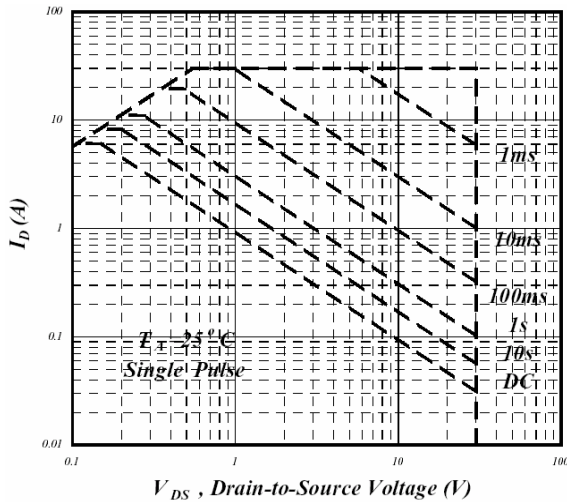


Fig 9. Maximum Safe Operating Area

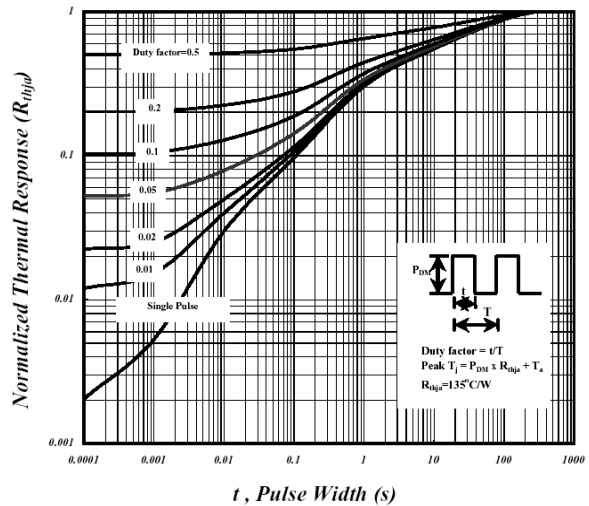


Fig 10. Effective Transient Thermal Impedance

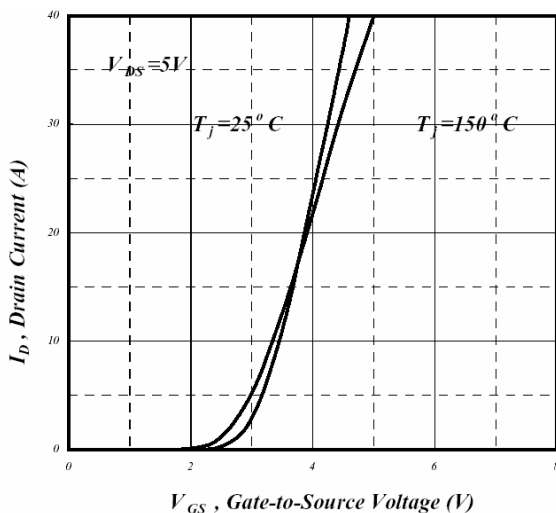


Fig 11. Transfer Characteristics

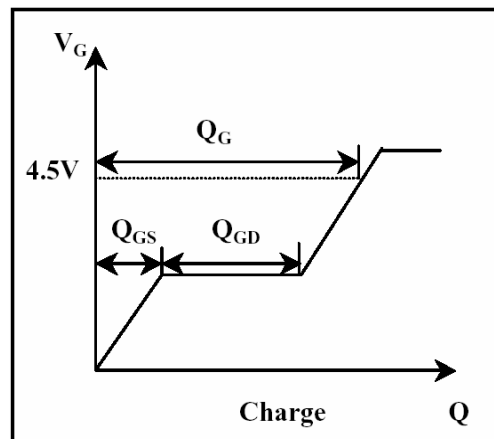
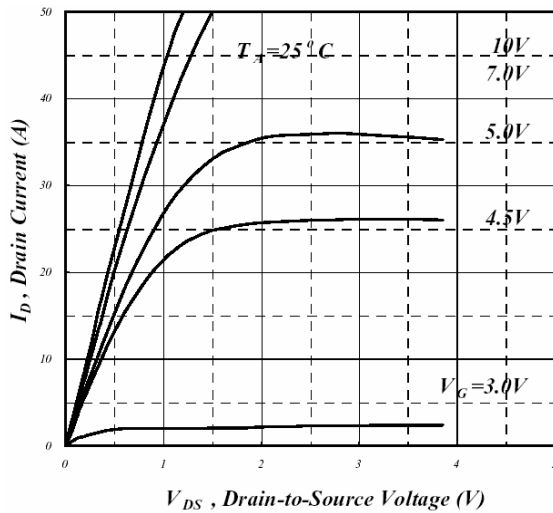
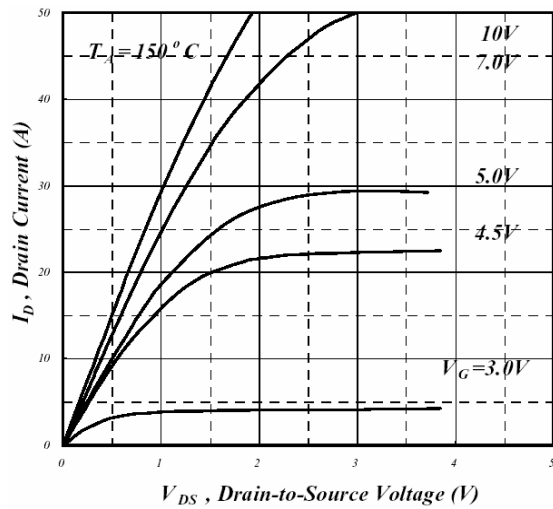


Fig 12. Gate Charge Waveform

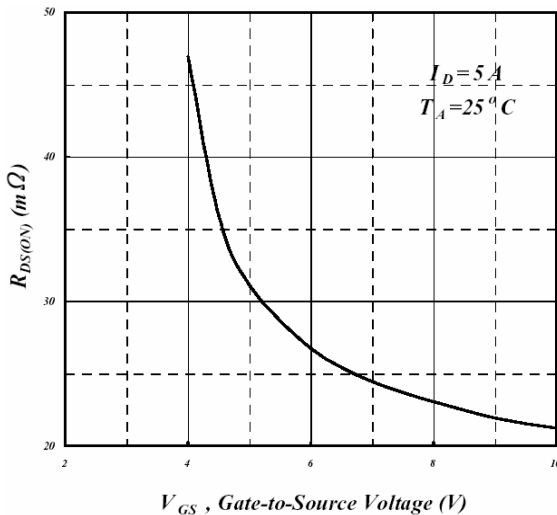
## CH-2



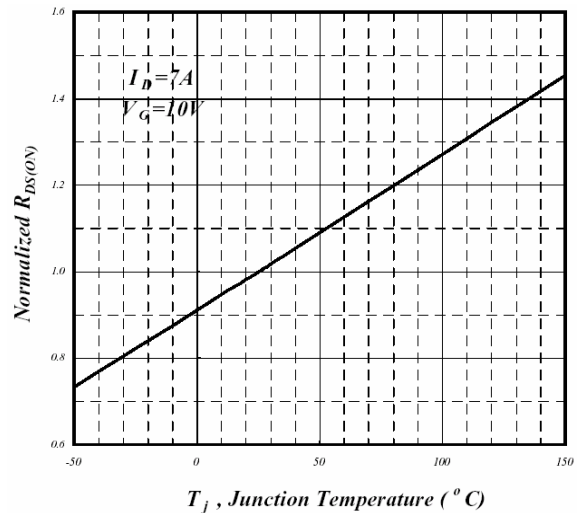
**Fig 1. Typical Output Characteristics**



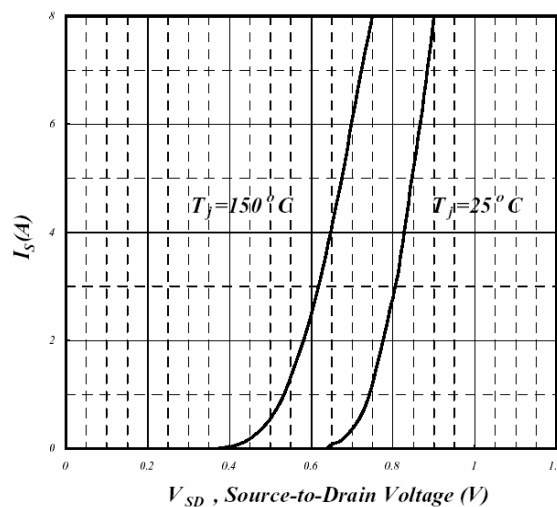
**Fig 2. Typical Output Characteristics**



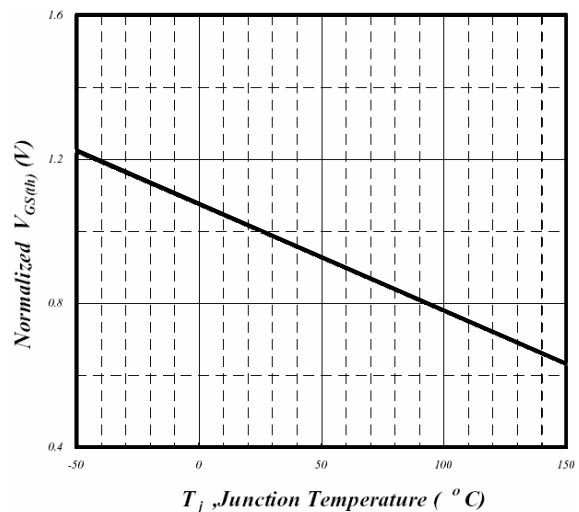
**Fig 3. On-Resistance v.s. Gate Voltage**



**Fig 4. Normalized On-Resistance v.s. Junction Temperature**

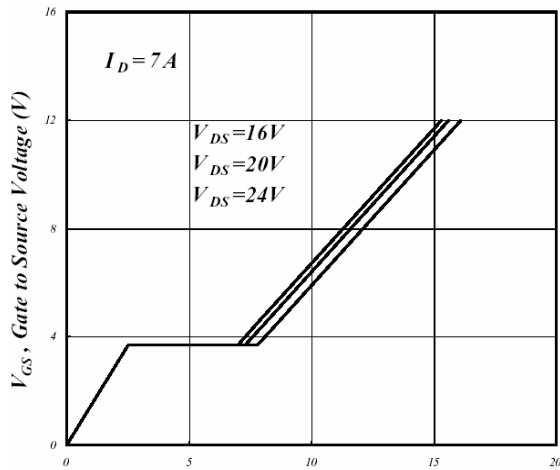


**Fig 5. Forward Characteristics of Reverse Diode**

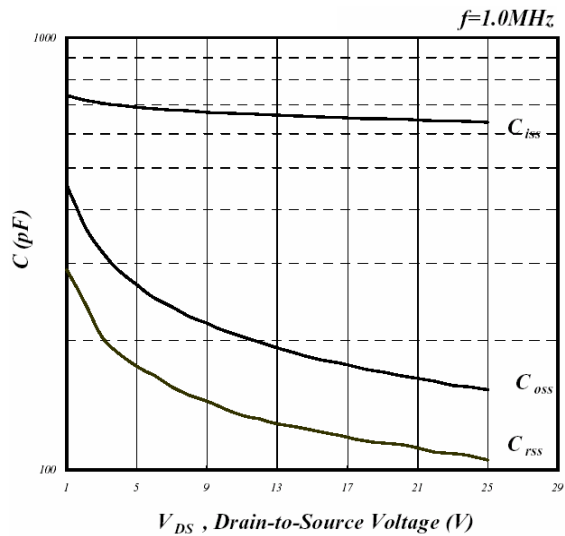


**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**

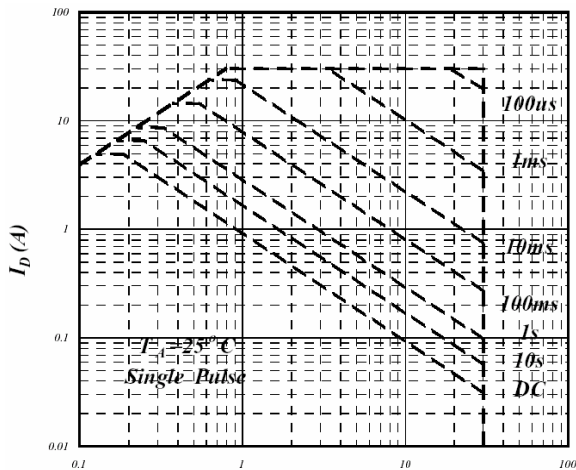
## CH-2



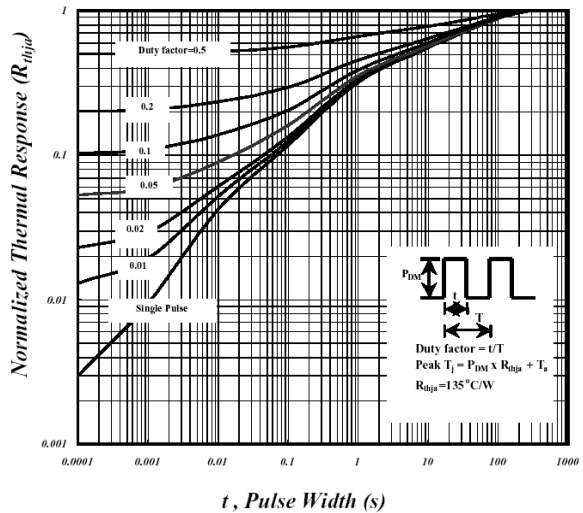
**Fig 7. Gate Charge Characteristics**



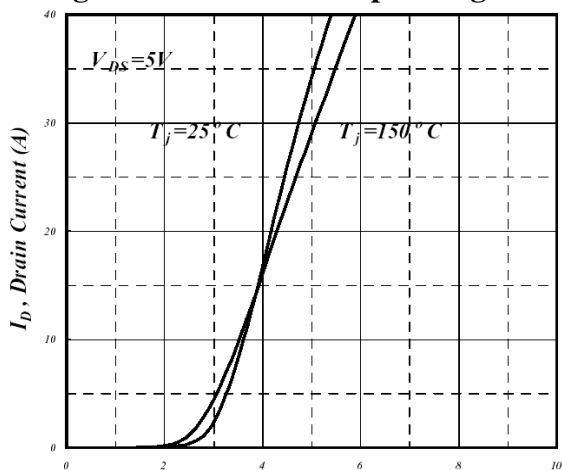
**Fig 8. Typical Capacitance Characteristics**



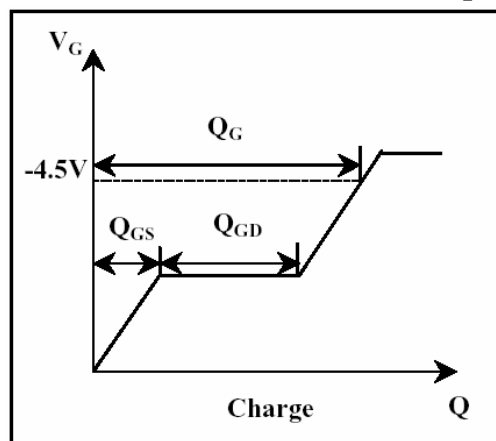
**Fig 9. Maximum Safe Operating Area**



**Fig 10. Effective Transient Thermal Impedance**



**Fig 11. Transfer Characteristics**



**Fig 12. Gate Charge Waveform**

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